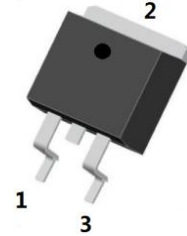


P/N: YZPST-BTA216B-600B/800B

TRIACS

●DESCRIPTION:

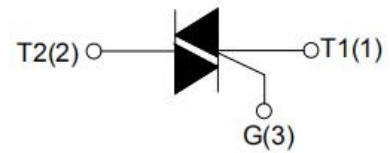
Due to separation glass passivation, these devices have good performance at dv/dt and reliability. The Triac series is suitable for general purpose AC switching. They can be used as an On-Off function in the applications such as static relays, heating regulation, or for phase control operation in light dimmers, motor speed controllers.



TO-263

●MAIN FEATURES

Symbol	Value	Unit
$I_{T(RMS)}$	16	A
V_{DRM}/V_{RRM}	600/800	V
I_{GT}	≤ 10	mA



●ABSOLUTE MAXIMUM RATINGS

Symbol	PARAMETER		Value	Unit
$I_{T(RMS)}$	RMS on-state current(full sine wave)	TO-263.Non-Ins $T_c \leq 99^\circ C$	16	A
I_{TSM}	Non repetitive surge peak on-state current (full sine wave, $T_j=25^\circ C$)	$t=20ms$	140	A
		$t=16.7ms$	150	
I^2t	I^2t Value for fusing	$t=10ms$	98	A^2S
di/dt	Repetitive rate of rise of on-state Current after triggering	$I_{TM} = 20 A; I_G = 0.2 A$ $di/dt = 0.2 A/us$	100	$A/\mu s$
I_{GM}	Peak gate current,	—	2	A
V_{GM}	Peak gate voltage	—	5	W
P_{GM}	Peak gate power	—	5	W
$P_{G(AV)}$	Average gate power	over any 20 ms period	0.5	W
T_{stg}	Storage junction temperature range	-40 to +150		$^\circ C$
T_j	Operating junction temperature range	125		$^\circ C$

● ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$, unless otherwise specified)

STATIC CHARACTERISTICS

Symbol	Parameter	Test Condition	Quadrant	Value			Unit
				MIN	TYPE	MAX	
I_{GT}	Gate trigger current	$V_D=12\text{V}, I_T=0.1\text{A}$	I-II-III	-	-	10	mA
V_{GT}	Gate trigger voltage	$V_D=12\text{V}, I_T=0.1\text{A}$		-	0.7	1.5	V
		$V_D=400\text{V}, I_T=0.1\text{A}, T_j=125^\circ\text{C}$		0.25	0.4	-	
V_T	On-state voltage	$I_T=20\text{A}$		-	1.2	1.5	V
I_H	Holding current	$V_D=12\text{V}, I_{GT}=0.1\text{A}$	I-II-III	-	-		mA
I_L	Latching current	$V_D=12\text{V}, I_{GT}=0.1\text{A}$	I-III	-	-	60	mA
			II	-	-	90	mA
I_D	Off-state leakage current	$V_D = V_{DRM(max)}; T_j = 125^\circ\text{C}$		-	0.1	0.5	mA

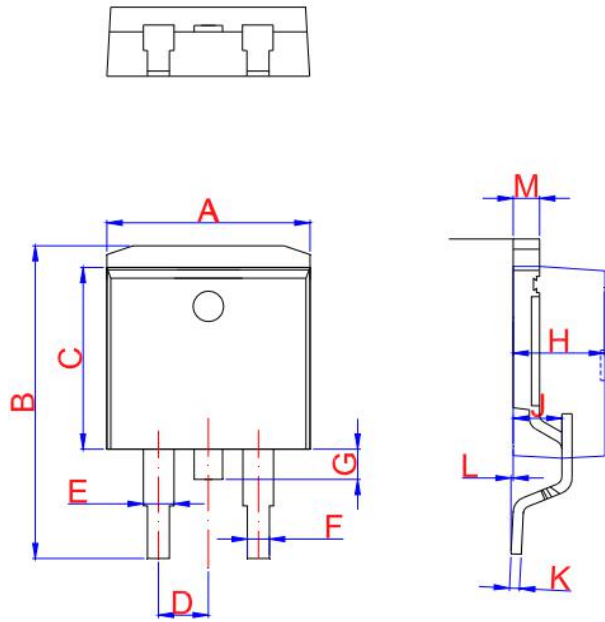
DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Condition	Value		Unit
			MIN	TYPE	
dV_D/dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125^\circ\text{C}$ exponential waveform; gate open circuit	1000	4000	V/us
dI_{com}/dt	Critical rate of change of commutating current	$V_{DM} = 400\text{V}; T_j = 125^\circ\text{C}; I_{T(RMS)} = 16\text{A};$ without snubber; gate open circuit		28	A/ms
t_{gt}	Gate controlled turn-on time	$I_{TM} = 20\text{A}; V_D = V_{DRM(max)}; I_G = 0.1\text{A}; dI_G/dt = 5\text{A}/\mu\text{s}$		2	us

● THERMAL RESISTANCES

Symbol	Parameter	Test Condition	Value			Unit
			MIN	TYPE	MAX	
$R_{th\ j-mb}$	Thermal resistance junction to mounting base	full cycle			1.2	K/W
		half cycle			1.7	
$R_{th\ j-a}$	Thermal resistance junction to ambient	In free air		60		K/W

PACKAGE MECHANICAL DATA



TO-263

Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	9.9		10.3	0.390		0.406
B	14.7		15.8	0.579		0.622
C	8.5		8.9	0.370		0.378
D		2.54			0.100	
E	1.20		1.40	0.047		0.055
F	0.75		0.85	0.029		0.033
G			1.75			0.069
H	4.40	4.60	4.80	0.173	0.181	0.189
J	2.40	2.60	2.80	0.094	0.102	0.110
L	0	0.1	0.25	0	0.004	0.010
M	1.17	1.27	1.37	0.046	0.05	0.054

ELECTRICAL CHARACTERISTICS (CURVES)

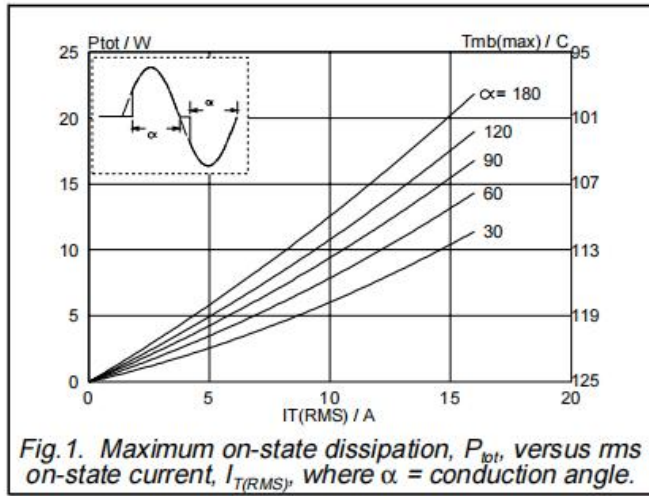


Fig. 1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where α = conduction angle.

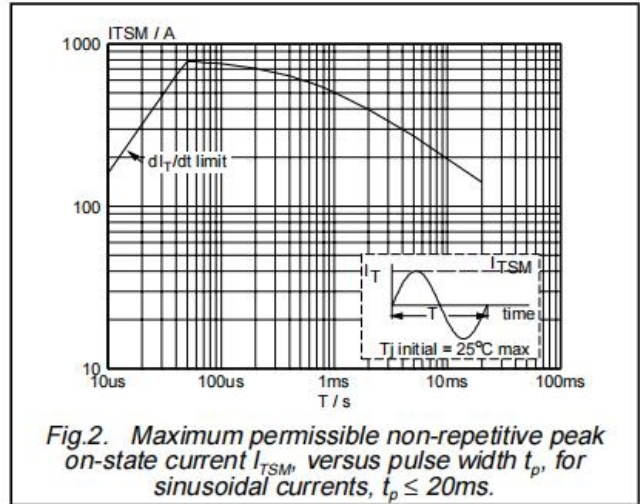


Fig. 2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \leq 20ms$.

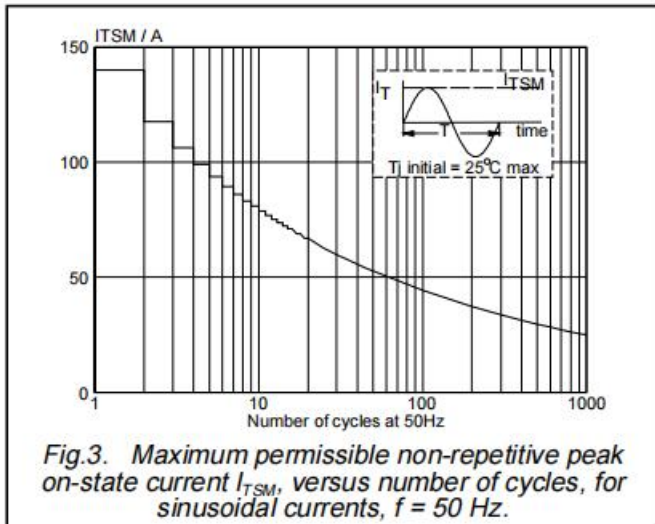


Fig. 3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, $f = 50 \text{ Hz}$.

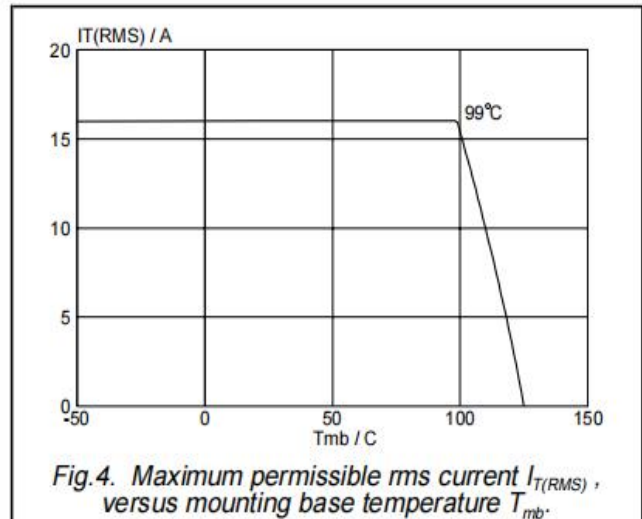


Fig. 4. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb} .

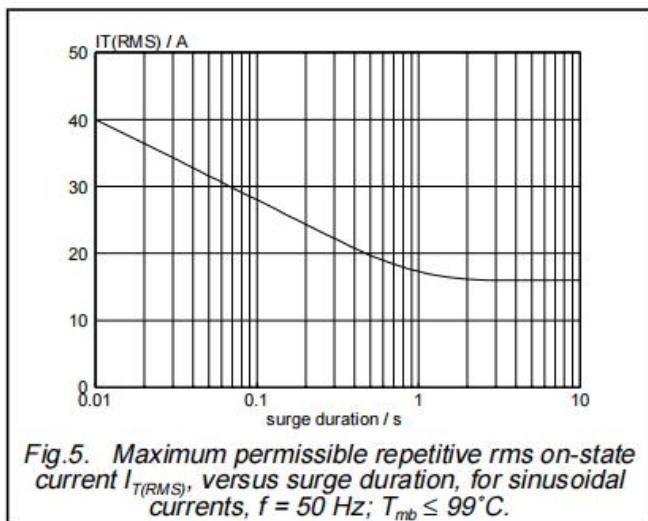


Fig. 5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, $f = 50 \text{ Hz}$; $T_{mb} \leq 99^\circ C$.

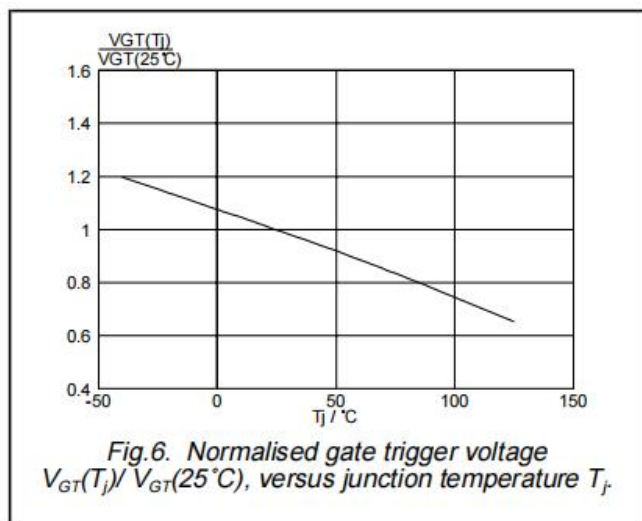


Fig. 6. Normalised gate trigger voltage $V_{GT}(T_j) / V_{GT}(25^\circ C)$, versus junction temperature T_j .

